

<b>Notice of References Cited</b>	Application/Control No. 10/807,670	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
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	B	US-6,749,487 B2	06-2004	Okuhata et al.	451/41
	C	US-2003/0109202 A1	06-2003	Matsuno et al.	451/41
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	M	US-			

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